


Form PTO-1449		 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1670		SERIAL NO. 09/881,407		
LIST OF ART CITED BY APPLICANT <small>(See 37 CFR 1.213 for sheets if necessary)</small>				APPLICANT Zhongze Wang				
				FILING DATE June 13, 2001		GROUP 2811		
U.S. PATENT DOCUMENTS								
*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
PEP	AA	5,254,489	10/19/93	Nakata				
PEP	AB	5,464,792	11/07/95	Tseng et al.				
PEP	AC	5,596,218	01/21/97	Soleimani et al.				
PEP	AD	5,620,908	04/15/97	Inoh et al.				
PEP	AE	5,674,788	10/07/97	Wristers et al.				
PEP	AF	5,716,864	02/10/98	Abe				
PEP	AG	5,960,302	09/28/99	Ma et al.				
PEP	AH	5,972,783	10/26/99	Arai et al.				
PEP	AI	5,994,749	11/30/99	Oda				
PEP	AJ	6,225,151	05/01/01	Gardner et al.				
PEP	AK	4,651,406	03/24/87	Shimizu et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
PEP	AL	WO 96/39713	12/12/96	PCT				
PEP	AM	JP06302813A	04/09/93	Japan (Citizen Watch Co. Ltd.)				
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
PEP	AR		Doyle et al., "Simultaneous Growth of Different Thickness Gate Oxides in Silicon CMOS Processing", IEEE Electron Device Letters, Vol. 16, No. 7.					
PEP	AS		Ko et al., "The Effect of Nitrogen Incorporation Into the Gate Oxide by Using Shallow Implantation of Nitrogen and Drive-in Process", 1998 IEEE, 0-7803-4932-6/98.					
	AT		Kurni et al., "The Effects of Nitrogen Implantation into P+ Poly-Silicon Gate on Gate Oxide Properties", 1994 Symposium on VLSI Technology Digest of Technical Papers, pp. 107-108.					
EXAMINER <i>Paula P. P. P.</i>				DATE CONSIDERED <i>17 Sept. 2002</i>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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<div style="display: flex; align-items: center;"> <div style="border: 1px solid black; border-radius: 50%; padding: 10px; text-align: center; margin-right: 10px;"> OIP OCT 15 2001 PATENT & TRADEMARK OFFICE </div> <div> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) </div> </div>				APPLICANT Zhongze Wang			
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
REP	AA	5,502,009	03/26/96	Lin			
REP	AB	6,136,654	10/24/00	Kraft et al.			
REP	AC	6,165,846	12/26/00	Carns et al.			
REP	AD	6,200,834-B1	03/13/01	Bronner et al.			
REP	AE	6,093,661	07/25/00	Trivedi et al.			
	AF						
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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
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	AO						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
REP	AR		C.T. Liu et al.; "Multiple Gate Oxide Thickness for 2GHz System-on-a-Chip Technologies"; IEEE 1998; pp. 21.2.1-21.2.4				
	AS						
	AT						
EXAMINER <i>Paula P. Patis</i>				DATE CONSIDERED 17 Sept. 2002			
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
REP	AA	5,763,922	06/09/98	Chau			
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	AC						
	AD						
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	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
REP	AM	326352	11/01	Japan			
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
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